

Powder Diffraction

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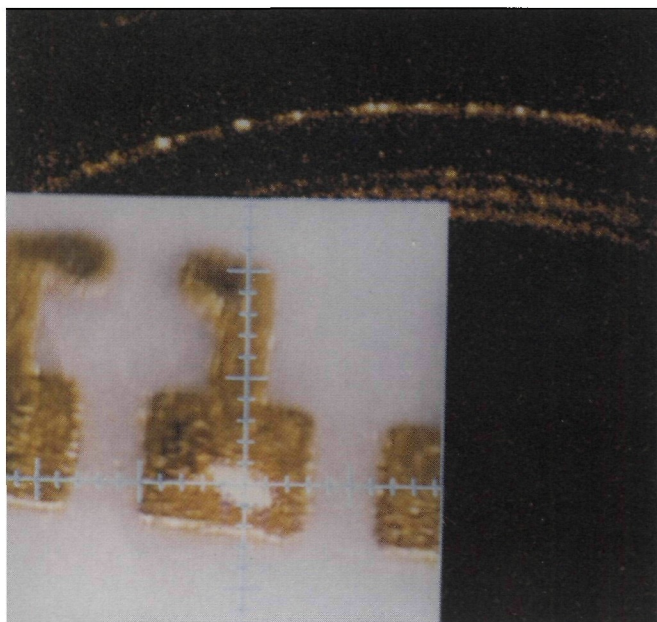
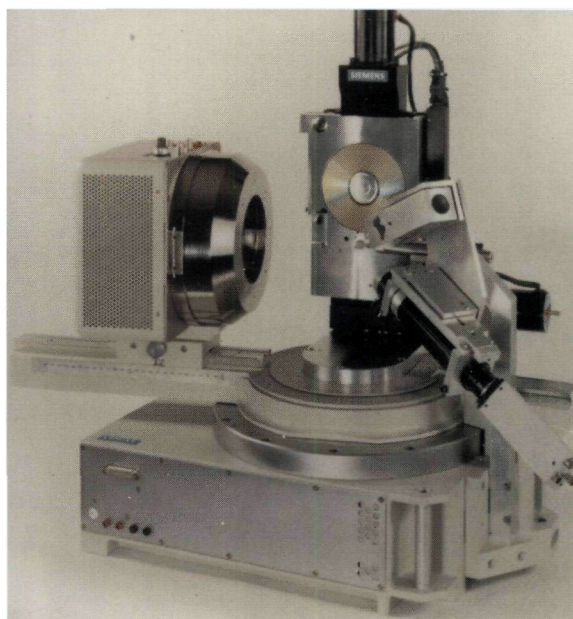


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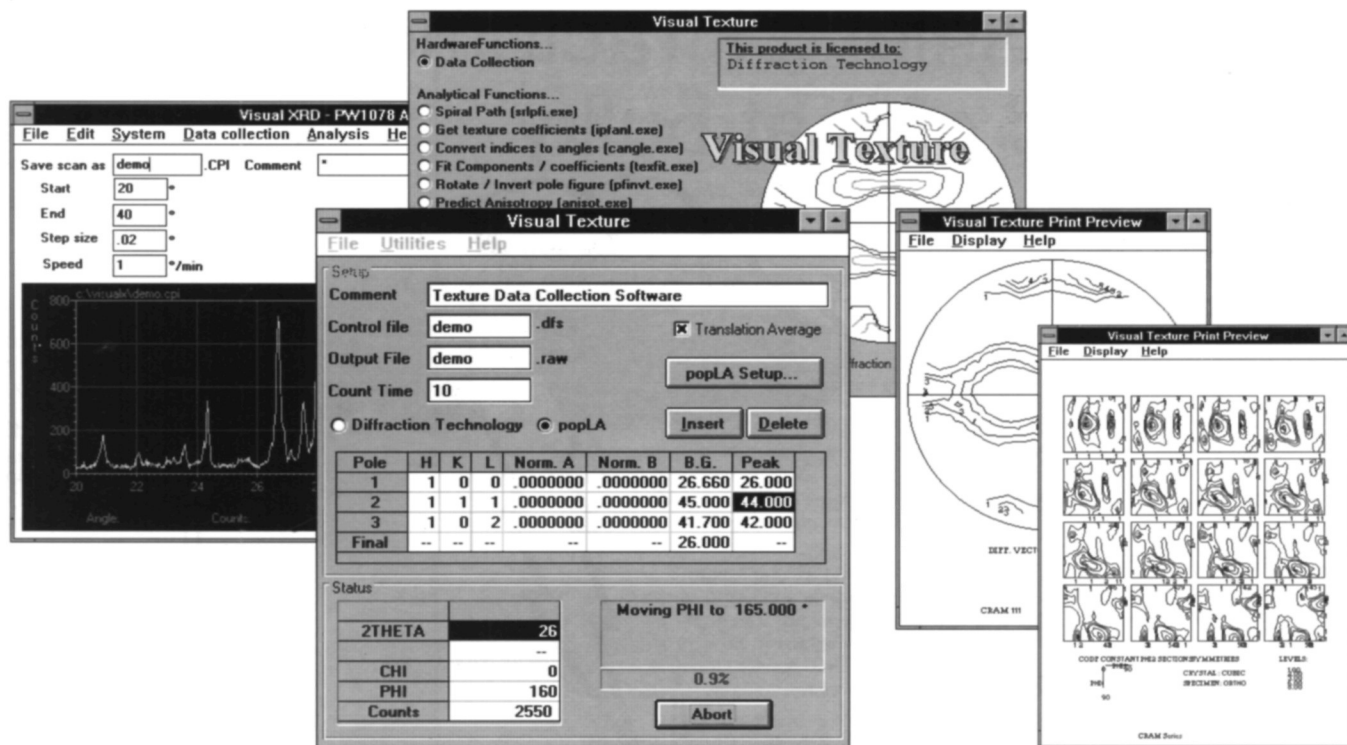
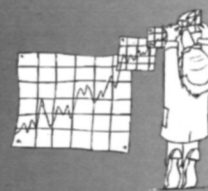
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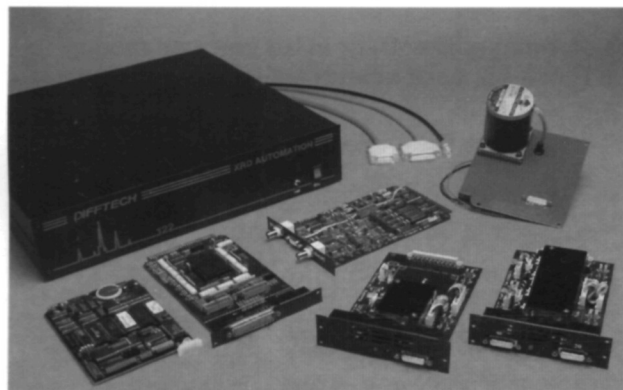
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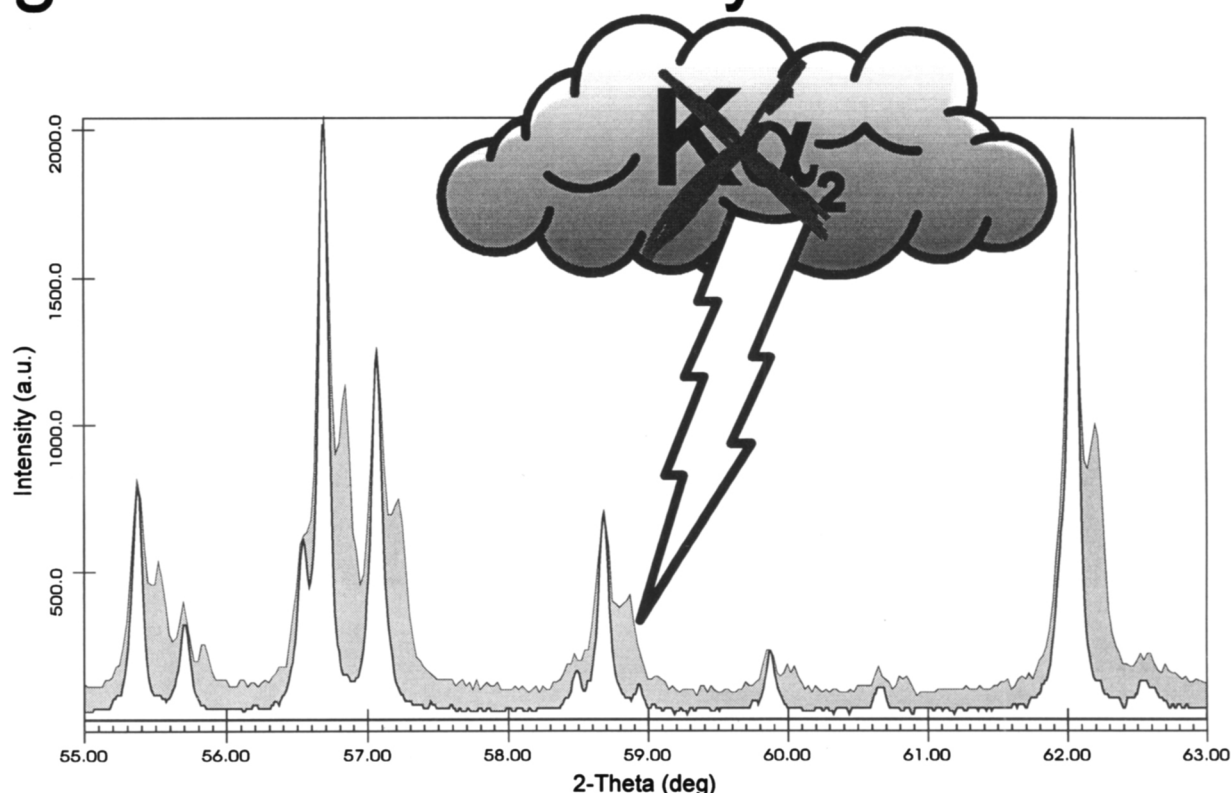
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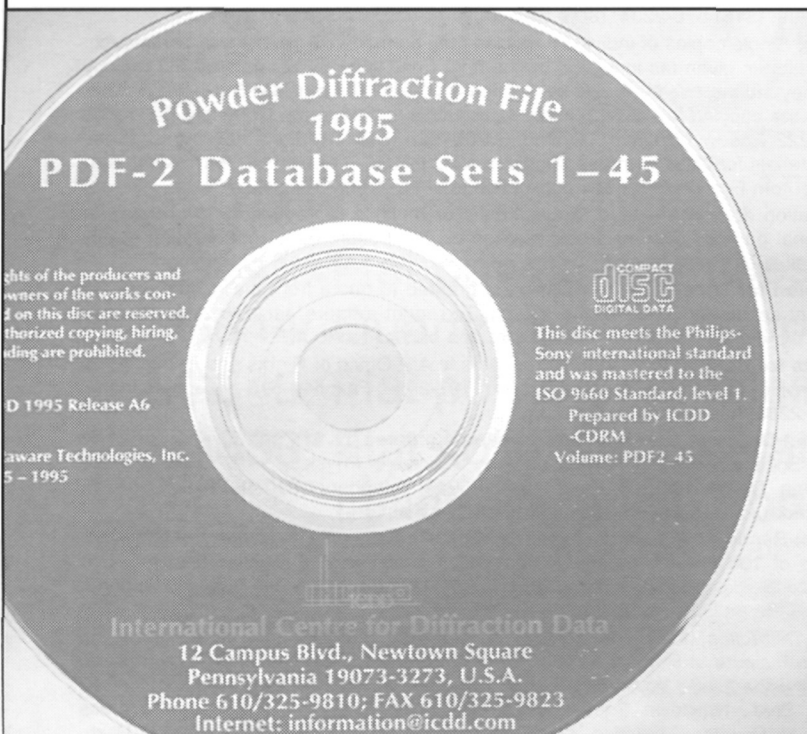
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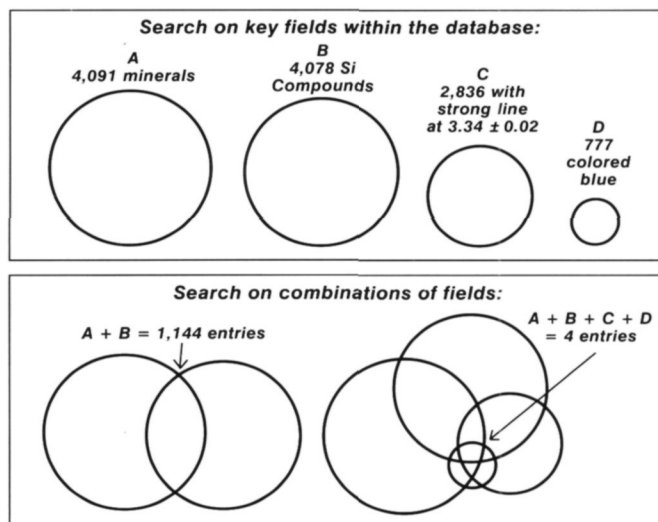
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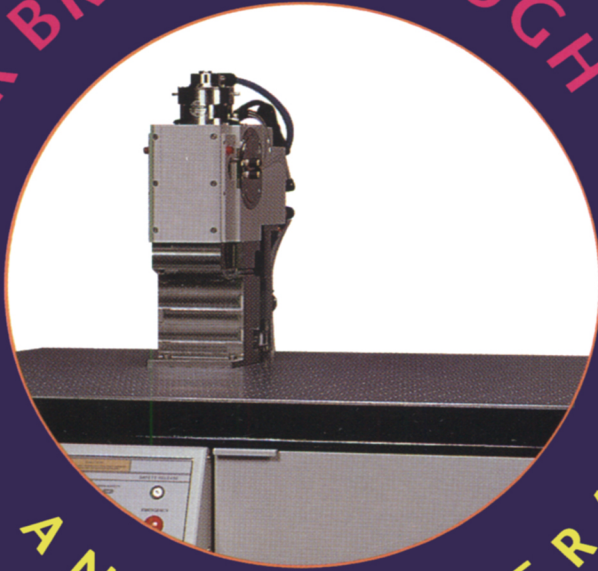
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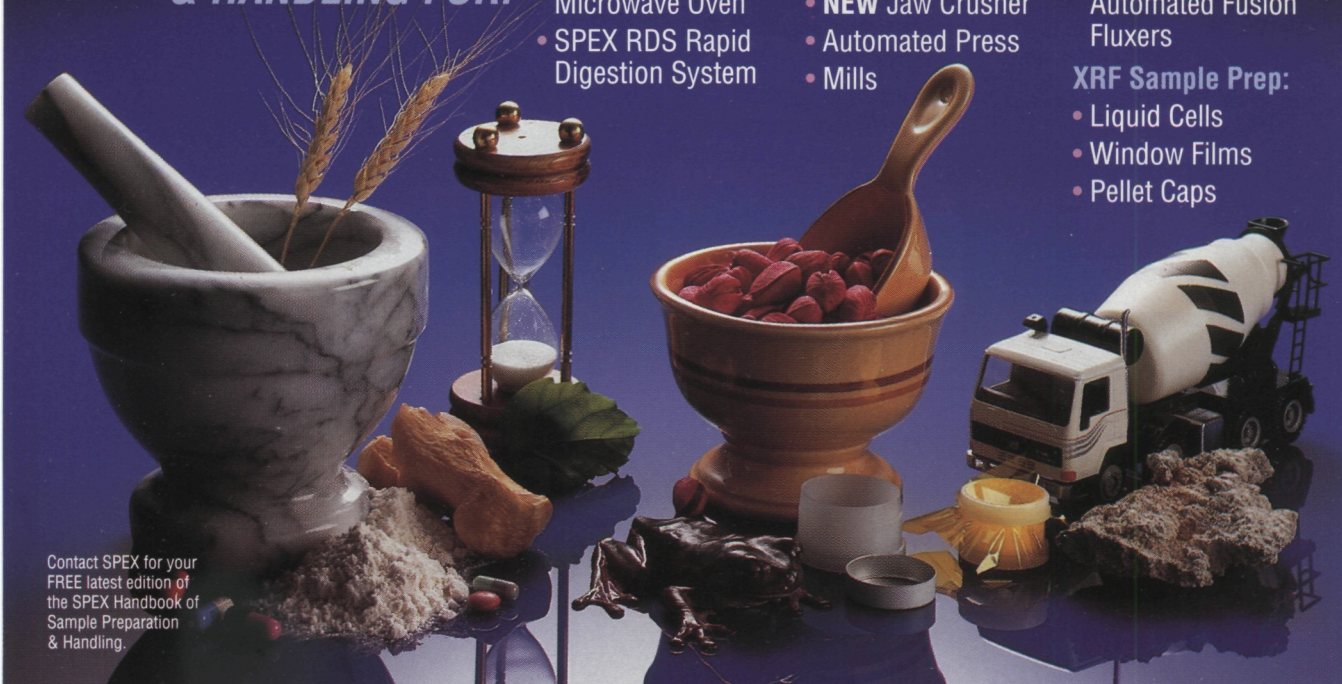
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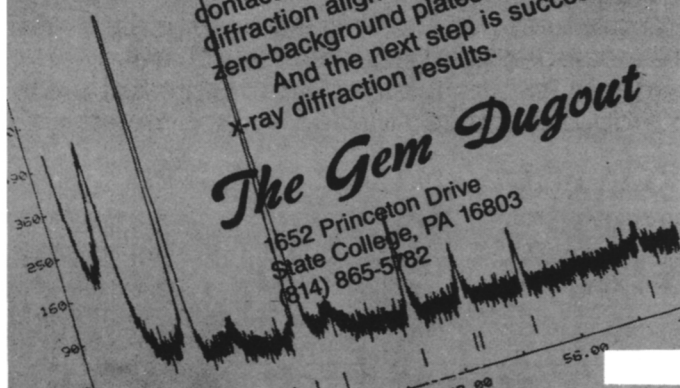
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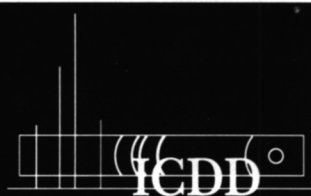
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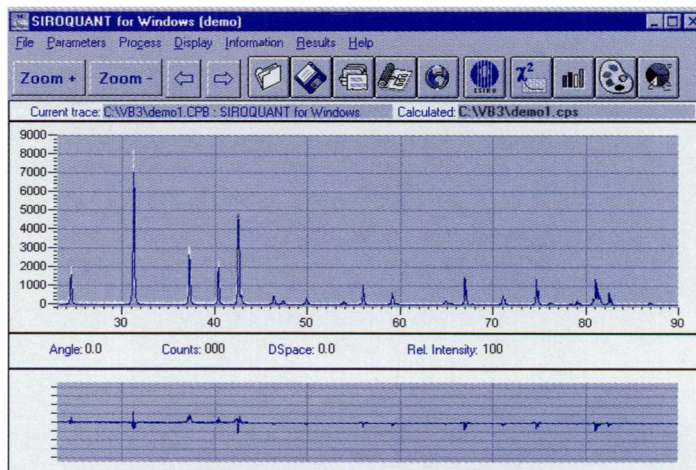
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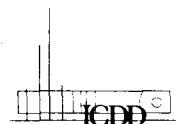
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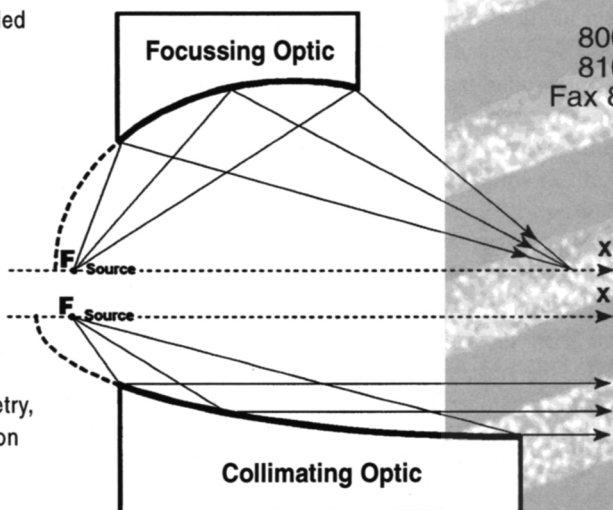
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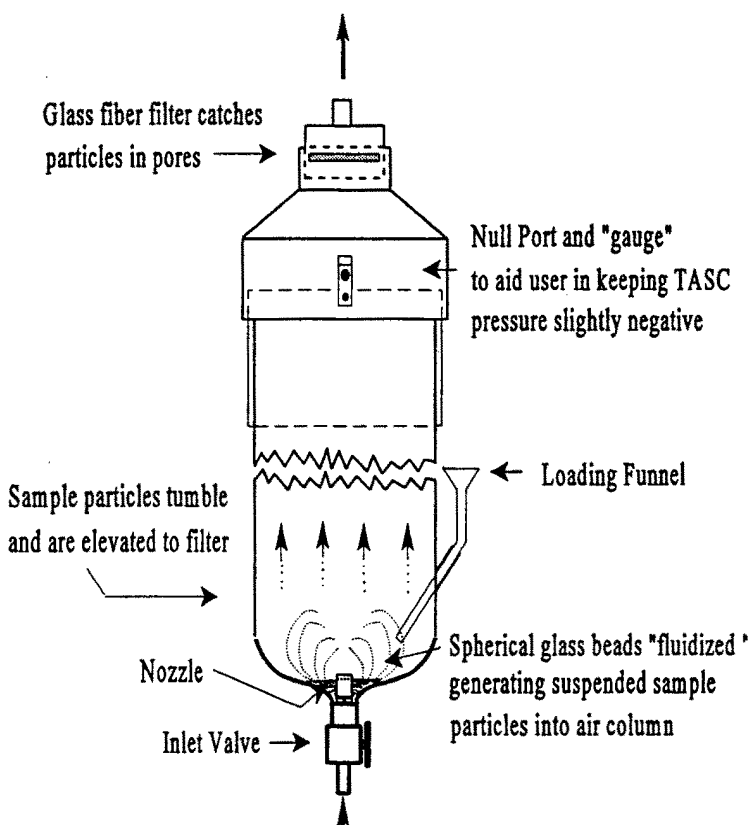
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June 10-14, 1996

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- Session I — Fundamentals of X-ray Fluorescence
June 17-21, 1996
- Session II — Advanced Methods in X-ray Fluorescence
June 24-28, 1996

The \$1,150 fee for each session includes textbook, lecture notes, use of computers, and lunch. Please direct all inquiries and requests for a comprehensive brochure (available January 1996) to:

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